

## **Effect of temperature on the action spectra of pristine and Cu-grafted titania**

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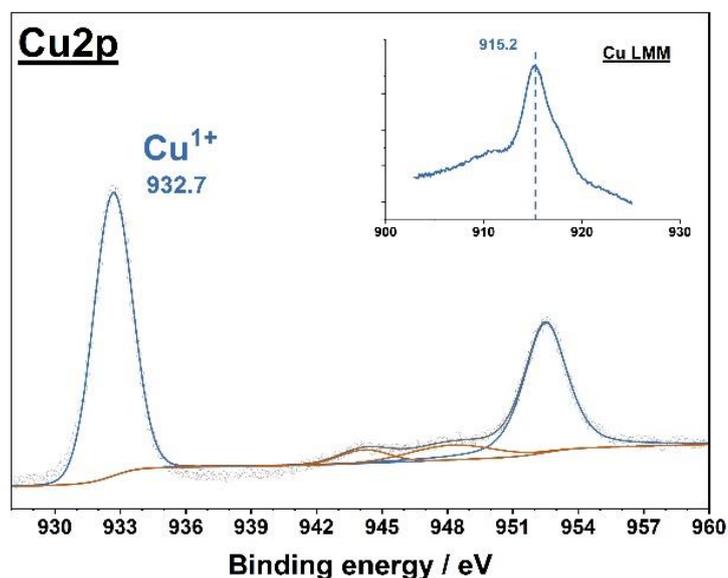
### ***1 Materials and catalyst characterization***

High purity grade acetone ( $\text{CH}_3\text{COCH}_3$ ) was used as received from AO REAHIM Inc. (Russia) without further purification as a test organic substrate in the photocatalytic experiments.  $\text{Cu}(\text{CH}_3\text{COO})_2$  from AO REAHIM Inc. (Russia) and  $\text{NaBH}_4$  from Acros Organics (USA) were used for the synthesis procedure. Commercially available  $\text{TiO}_2$  powder EuroSupport (100% anatase,  $a_{\text{s,BET}} = 380 \text{ m}^2 \text{ g}^{-1}$ ) from Euro Support Manufacturing Czechia (Czech Republic) was employed as photocatalysts. The modified  $\text{TiO}_2$  photocatalyst was synthesized via the impregnation of basic photocatalyst with an aqueous solution of precursor  $\text{Cu}(\text{CH}_3\text{COO})_2$  followed by chemical reduction with a 3-fold excess of  $\text{NaBH}_4$ , washing in a centrifuge for 5 times, and drying at  $110 \text{ }^\circ\text{C}$ . The amount of precursor was determined by the required metal content (wt.%) in the catalyst. The details of synthesis can be found elsewhere [S1].

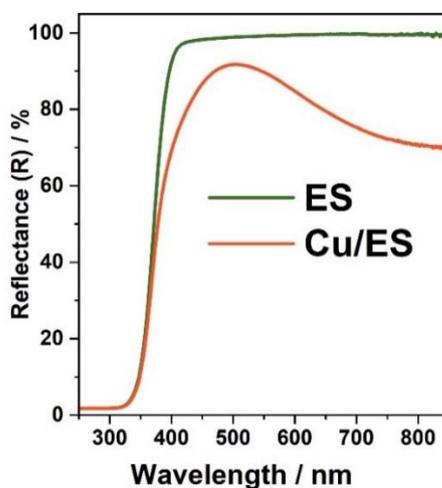
The textural properties were investigated by  $\text{N}_2$  adsorption at 77 K using an ASAP 2400 instrument (Micromeritics, USA). A specific surface area values were calculated by BET analysis: ca.  $320 \text{ m}^2 \text{ g}^{-1}$  for the synthesized Cu/ES catalyst and  $380 \text{ m}^2 \text{ g}^{-1}$  for pristine ES  $\text{TiO}_2$ , respectively. The UV-Vis diffuse reflectance spectra were recorded in the range of 250–850 nm with 1 nm of resolution using a Cary 300 UV-Vis spectrophotometer from Agilent (USA) equipped with a DRA-301 diffuse reflectance accessory at room temperature. A pre-packed PTFE from Agilent (USA) was used. The X-ray photoelectron spectra were measured on a SPECS spectrometer with a PHOIBOS-150-MCD-9 analyzer ( $\text{AlK}\alpha$  radiation,  $h\nu = 1486.6 \text{ eV}$ , 150 W). The binding energy (BE) scale was pre-calibrated using the positions of the peaks of  $\text{Au}4f_{7/2}$  (BE = 84.0 eV) and  $\text{Cu}2p_{3/2}$  (BE = 932.67 eV) core levels. The samples were loaded onto a conducting double-sided copper scotch. The  $\text{Ti}2p_{3/2}$  peak at 458.8 eV of the titanium oxide support was used as an internal standard [S2]. The survey spectrum and the narrow spectra were registered at the analyzer pass energy 20 eV.

A Bruker D8 Advance diffractometer with an Anton Paar XRK900 reaction camera (Austria) with  $\text{CuK}\alpha$  radiation ( $\lambda = 1.5418 \text{ \AA}$ ) and a focusing geometry  $\theta$ - $\theta$  was used to capture diffraction data

in the *in-situ* mode. A one-dimensional LynxEye detector was used to register the signal. The shooting range of  $2\theta$  was  $20-80^\circ$  with a step of  $0.05^\circ$  and an accumulation time of 3 seconds at the point. The samples were heated at a rate of  $12^\circ\text{C min}^{-1}$ . The X-ray recording began immediately when the set temperature was reached. The phase composition of the samples was determined using the ICDD PDF-2 database. The structural data is obtained from the ICSD database. For the data obtained, a full-profile analysis was performed by the Rietveld method using the TOPAS V.4.3 software. To describe the instrumental broadening, an external standard was used – a powder of metallic silicon taken under identical conditions. The size of the coherent scattering region (OCR) was calculated from the value of the integral width to obtain the volume-weighted mean column lengths based on integral breadth (LVol-IB). When modeling the diffraction data by the Rietveld method, the lattice parameters and the sizes of the CSR of the phases were refined.



**Figure S1** Deconvolution of XPS spectra for Cu/ES sample.



**Figure S2** UV-vis diffuse reflectance spectra.

## 2 Photocatalytic experiments

The photocatalytic experiments were performed in a continuous-flow set-up using the volume flow rate  $0.1 \pm 0.02 \text{ L min}^{-1}$ , the inlet concentration of acetone  $38 - 42 \mu\text{mol L}^{-1}$ , the relative humidity of pre-cleaned inlet air  $20 \pm 2\%$  at  $25 \text{ }^\circ\text{C}$ . The set-up was connected to Bruker Vector 22 FTIR spectrometer (USA) to monitor periodically the changes in the gas phase.  $\text{CO}_2$  generation rate was selected for the measure of activity [S3]. The temperature of the reactor was controlled via a PC-connected thermostatic unit so that the temperature was adjusted in the range of  $40\text{-}140 \text{ }^\circ\text{C}$ . Typical methodology of photocatalysts' pretreatment and sampling: catalyst was suspended in deionized water, treated using ultrasound, next suspension was deposited onto a glass plate (ca.  $9.1 \text{ cm}^2$ ) at a surface density of  $1 \text{ mg cm}^{-2}$ , and dried at  $110 \text{ }^\circ\text{C}$  for 2 h to remove water from the sample. The light source was turned on at 40-min point to ensure the absence of activity without irradiation of the sample. A set of light-emitting diode plates (LEDs) with a special collimating lens were employed for the photocatalyst irradiation during the experiments following the methodology presented elsewhere [S3]. All LEDs were used as adjusted to the photon flux of  $1.5 \cdot 10^{17} \text{ photons s}^{-1}$  (i.e.,  $0.25 \mu\text{E s}^{-1}$ , or  $15 \mu\text{E min}^{-1}$ ). The photonic efficiency during acetone photocatalytic oxidation is calculated as the activity value ( $\text{CO}_2$  generation rate,  $\mu\text{mol min}^{-1}$ ) divided by the total flux of photons incident onto the surface of catalyst per time interval ( $\mu\text{E min}^{-1}$ ).

## References

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- [S2] J.F. Moulder, W.F. Stickle, P.E. Sobol and K.D. Bomben, Handbook of X-Ray Photoelectron Spectroscopy: A Reference Book of Standard Spectra for Identification and Interpretation of XPS Data, Physical Electronics Division, Perkin-Elmer Corporation, USA, 1992.
- [S3] M. Lyulyukin, N. Kovalevskiy, D. Selishchev and D. Kozlov, *J. Photochem. Photobiol., A*, 2021, **405**, 112981.